

Title (en)

METHOD FOR DETERMINING TEMPERATURES ON SEMICONDUCTOR COMPONENTS

Title (de)

VERFAHREN ZUR BESTIMMUNG VON TEMPERATUREN AN HALBLEITERBAUELEMENTEN

Title (fr)

PROCEDE DE DETERMINATION DE TEMPERATURES SUR DES ELEMENTS A SEMI-CONDUCTEURS

Publication

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Application

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Abstract (en)

[origin: WO02086432A1] The aim of the invention is to determine a temperature on a semiconductor component (1). To this end, an inquiry light wave (7) is irradiated onto a measuring point located on the semiconductor component, a response light wave (8, 8') radiated by the measuring point is detected, and the temperature of the measuring point is determined on the basis of a temperature-dependent property (R) of the response light wave (8, 8').

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